Olivier Thomas

List of Publications by Year in descending order

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240 papers

5,461 citations

40 h-index 60 g-index

242 all docs 242 docs citations

times ranked

242

3898 citing authors

#	Article	IF	CITATIONS
1	Crystallographic Anisotropy Dependence of Interfacial Sliding Phenomenon in a Cu(16)/Nb(16) ARB (Accumulated Rolling Bonding) Nanolaminate. Nanomaterials, 2022, 12, 308.	1.9	3
2	A nonlinear piezoelectric shunt absorber with 2:1 internal resonance: experimental proof of concept. Smart Materials and Structures, 2022, 31, 035006.	1.8	9
3	A nonlinear piezoelectric shunt absorber with a 2:1 internal resonance: Theory. Mechanical Systems and Signal Processing, 2022, 170, 108768.	4.4	21
4	Time-resolved piezoelectric response in relaxor ferroelectric (Pb _{0.88} La _{0.12})(Zr _{0.52} Ti _{0.48})O ₃ thin films. Journal of Applied Physics, 2022, 131, 064102.	1.1	1
5	X-ray Diffraction Imaging of Deformations in Thin Films and Nano-Objects. Nanomaterials, 2022, 12, 1363.	1.9	3
6	On the dynamic stability and efficiency of centrifugal pendulum vibration absorbers with rotating pendulums. Journal of Sound and Vibration, 2022, 536, 117157.	2.1	8
7	Reply to the commentary written by M. Zurru on the paper "Backbone curves of coupled cubic oscillators in one-to-one internal resonance: bifurcation scenario, measurements and parameter identificationâ€; by Arthur Givois, Jin-Jack Tan, Cyril Touzé and Olivier Thomas, http://doi.org/10.1007/s11012-020-01132-2. Meccanica. 2021. 56. 243-244.	1.2	0
8	Enhancement of a dynamic vibration absorber by means of an electromagnetic shunt. Journal of Intelligent Material Systems and Structures, 2021, 32, 331-354.	1.4	19
9	Guidelines for the layout and tuning of piezoelectric resonant shunt with negative capacitances in terms of dynamic compliance, mobility and accelerance. Journal of Intelligent Material Systems and Structures, 2021, 32, 2092-2107.	1.4	3
10	Comparison of Reduction Methods for Finite Element Geometrically Nonlinear Beam Structures. Vibration, $2021, 4, 175-204$.	0.9	28
11	Simultaneous Multi-Bragg Peak Coherent X-ray Diffraction Imaging. Crystals, 2021, 11, 312.	1.0	6
12	Model order reduction methods for geometrically nonlinear structures: a review of nonlinear techniques. Nonlinear Dynamics, 2021, 105, 1141-1190.	2.7	78
13	Piezoelectric nanoelectromechanical systems integrating microcontact printed lead zirconate titanate films. Journal of Micromechanics and Microengineering, 2020, 30, 035004.	1.5	4
14	Experimental analysis of nonlinear resonances in piezoelectric plates with geometric nonlinearities. Nonlinear Dynamics, 2020, 102, 1451-1462.	2.7	8
15	Direct Observations of the Structural Properties of Semiconducting Polymer: Fullerene Blends under Tensile Stretching. Materials, 2020, 13, 3092.	1.3	1
16	First stages of plasticity in three-point bent Au nanowires detected by in situ Laue microdiffraction. Applied Physics Letters, 2020, 116, 243101.	1.5	1
17	Piezoelectric Properties of Pb1â^'xLax(Zr0.52Ti0.48)1â^'x/4O3 Thin Films Studied by In Situ X-ray Diffraction. Materials, 2020, 13, 3338.	1.3	3
18	Non-intrusive reduced order modelling for the dynamics of geometrically nonlinear flat structures using three-dimensional finite elements. Computational Mechanics, 2020, 66, 1293-1319.	2.2	39

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19	Very large amplitude vibrations of flexible structures: Experimental identification and validation of a quadratic drag damping model. Journal of Fluids and Structures, 2020, 97, 103056.	1.5	18
20	Theoretical and experimental investigation of a 1:3 internal resonance in a beam with piezoelectric patches. JVC/Journal of Vibration and Control, 2020, 26, 1119-1132.	1.5	18
21	Power System Nonlinear Modal Analysis Using Computationally Reduced Normal Form Method. Energies, 2020, 13, 1249.	1.6	6
22	Stress Buildup Upon Crystallization of GeTe Thin Films: Curvature Measurements and Modelling. Nanomaterials, 2020, 10, 1247.	1.9	2
23	In situ measurements of the structure and strain of a π-conjugated semiconducting polymer under mechanical load. Journal of Applied Physics, 2020, 127, 045108.	1.1	8
24	A comparison of robustness and performance of linear and nonlinear Lanchester dampers. Nonlinear Dynamics, 2020, 100, 269-287.	2.7	9
25	Backbone curves of coupled cubic oscillators in one-to-one internal resonance: bifurcation scenario, measurements and parameter identification. Meccanica, 2020, 55, 481-503.	1.2	29
26	A New Fast Track to Nonlinear Modal Analysis of Power System Using Normal Form. IEEE Transactions on Power Systems, 2020, 35, 3247-3257.	4.6	11
27	A purely frequency based Floquet-Hill formulation for the efficient stability computation of periodic solutions of ordinary differential systems. Journal of Computational Physics, 2020, 416, 109477.	1.9	47
28	Numerical antiresonance continuation of structural systems. Mechanical Systems and Signal Processing, 2019, 116, 963-984.	4.4	22
29	Dynamic simulation and optimization of artificial insect-sized flapping wings for a bioinspired kinematics using a two resonant vibration modes combination. Journal of Sound and Vibration, 2019, 460, 114883.	2.1	5
30	Nonlinear polarization coupling in freestanding nanowire/nanotube resonators. Journal of Applied Physics, 2019, 125, .	1.1	4
31	On the frequency response computation of geometrically nonlinear flat structures using reduced-order finite element models. Nonlinear Dynamics, 2019, 97, 1747-1781.	2.7	49
32	In depth characterization of Ge-Si core-shell nanowires using X-ray coherent diffraction and time resolved pump-probe spectroscopy. Journal of Applied Physics, 2019, 126, 204304.	1.1	1
33	A Novel Method for Accelerating the Analysis of Nonlinear Behaviour of Power Grids using Normal Form Technique. , 2019, , .		0
34	Controlling dislocation nucleation-mediated plasticity in nanostructures via surface modification. Acta Materialia, 2019, 166, 572-586.	3.8	40
35	Progress of in situ synchrotron X-ray diffraction studies on the mechanical behavior of materials at small scales. Progress in Materials Science, 2018, 94, 384-434.	16.0	50
36	Identification of nonlinear modes using phase-locked-loop experimental continuation and normal form. Mechanical Systems and Signal Processing, 2018, 106, 430-452.	4.4	53

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37	A finite element/quaternion/asymptotic numerical method for the 3D simulation of flexible cables. Finite Elements in Analysis and Design, 2018, 139, 14-34.	1.7	11
38	An Accurate Third-Order Normal Form Approximation for Power System Nonlinear Analysis. IEEE Transactions on Power Systems, 2018, 33, 2128-2139.	4.6	33
39	Strain Distribution Induced in SOI Photonic Substrate by Through Silicon via Using Advanced Scanning X-Ray Nano-Diffraction. IEEE Transactions on Device and Materials Reliability, 2018, 18, 529-533.	1.5	2
40	Three-point bending behavior of a Au nanowire studied by <i>in-situ</i> Laue micro-diffraction. Journal of Applied Physics, 2018, 124, .	1.1	5
41	Low-temperature intrinsic plasticity in silicon at small scales. Acta Materialia, 2018, 161, 54-60.	3.8	25
42	Micromachiningâ€Compatible, Facile Fabrication of Polymer Nanocomposite Spin Crossover Actuators. Advanced Functional Materials, 2018, 28, 1801970.	7.8	42
43	Piezoelectric resonant shunt enhancement by negative capacitances: Optimisation, performance and resonance cancellation. Journal of Intelligent Material Systems and Structures, 2018, 29, 2581-2606.	1.4	29
44	Two modes resonant combined motion for insect wings kinematics reproduction and lift generation. Europhysics Letters, 2018, 121, 66001.	0.7	11
45	Effects of internal resonances in the pitch glide of Chinese gongs. Journal of the Acoustical Society of America, 2018, 144, 431-442.	0.5	7
46	Nonlinear Modes of Vibration and Internal Resonances in Nonlocal Beams. Journal of Computational and Nonlinear Dynamics, 2017, 12, .	0.7	11
47	Fabrication and characterization of mechanical resonators integrating microcontact printed PZT films. , 2017, , .		1
48	Coupling of Two Resonant Modes for Insect Wing Mimicking in a Flexible-Wing NAV and Generate Lift., 2017, , .		1
49	Improved shunt damping with two negative capacitances: An efficient alternative to resonant shunt. Journal of Intelligent Material Systems and Structures, 2017, 28, 2222-2238.	1.4	19
50	Normal form based analytical investigation of nonlinear power system dynamics under excitation. , $2017,$		0
51	Analytical investigation of nonlinear interactions between Voltage Source Converters interconnected to a transmission grid. , 2016 , , .		2
52	Hardening/softening behavior and reduced order modeling of nonlinear vibrations of rotating cantilever beams. Nonlinear Dynamics, 2016, 86, 1293-1318.	2.7	71
53	Third-order based analytical investigation of nonlinear interactions between voltage source converters interconnected to a transmission grid., 2016,,.		2
54	Improved resistive shunt by means of negative capacitance: new circuit, performances and multi-mode control. Smart Materials and Structures, 2016, 25, 075033.	1.8	63

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55	High-K thin films as dielectric transducers for flexural M/NEMS resonators. , 2016, , .		1
56	Optimization of Length and Thickness of Smart Transduction Layers on Beam Structures for Control and M/NEMS Applications. , 2015, , .		6
57	A New Electrical Circuit With Negative Capacitances to Enhance Resistive Shunt Damping. , 2015, , .		9
58	Conservative numerical methods for the Full von $K\tilde{A}_i$ rm \tilde{A}_i n plate equations. Numerical Methods for Partial Differential Equations, 2015, 31, 1948-1970.	2.0	10
59	Wafer-scale fabrication of self-actuated piezoelectric nanoelectromechanical resonators based on lead zirconate titanate (PZT). Journal of Micromechanics and Microengineering, 2015, 25, 035002.	1.5	19
60	<i>In situ</i> bending of an Au nanowire monitored by micro Laue diffraction. Journal of Applied Crystallography, 2015, 48, 291-296.	1.9	34
61	Strain and tilt mapping in silicon around copper filled TSVs using advanced X-ray nano-diffraction. Microelectronic Engineering, 2015, 137, 117-123.	1.1	13
62	Thermo-mechanical characterization of passive stress sensors in Si interposer. Microelectronics Reliability, 2015, 55, 738-746.	0.9	2
63	Through-silicon via-induced strain distribution in silicon interposer. Applied Physics Letters, 2015, 106,	1.5	13
64	Identification of mode couplings in nonlinear vibrations of the steelpan. Applied Acoustics, 2015, 89, 1-15.	1.7	16
65	Scanning force microscope forin situnanofocused X-ray diffraction studies. Journal of Synchrotron Radiation, 2014, 21, 1128-1133.	1.0	33
66	First stage of CoSi2 formation during a solid-state reaction. Journal of Applied Physics, 2014, 116, 245301.	1.1	6
67	Direct Observation of Gigahertz Coherent Guided Acoustic Phonons in Free-Standing Single Copper Nanowires. Journal of Physical Chemistry Letters, 2014, 5, 4100-4104.	2.1	32
68	Nonlinear forced vibrations of thin structures with tuned eigenfrequencies: the cases of 1:2:4 and 1:2:2 internal resonances. Nonlinear Dynamics, 2014, 75, 175-200.	2.7	21
69	New insights into single-grain mechanical behavior from temperature-dependent 3-D coherent X-ray diffraction. Acta Materialia, 2014, 78, 46-55.	3.8	15
70	Silicide formation during reaction between Ni ultra-thin films and Si(001) substrates. Materials Letters, 2014, 116, 139-142.	1.3	11
71	Singular inextensible limit in the vibrations of post-buckled rods: Analytical derivation and role of boundary conditions. Journal of Sound and Vibration, 2014, 333, 962-970.	2.1	5
72	Monitoring of methotrexate chlorination in water. Water Research, 2014, 57, 67-75.	5.3	27

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73	Anomalous coherent diffraction of core-shell nano-objects: A methodology for determination of composition and strain fields. Physical Review B, 2013, 87, .	1.1	7
74	Piezoelectric parametric amplifiers with integrated actuation and sensing capabilities. , 2013, , .		0
75	CoSi2 ultra-thin layer formation kinetics and texture from X-ray diffraction. Thin Solid Films, 2013, 541, 17-20.	0.8	1
76	Concentration and Strain Fields inside a Ag/Au Core–Shell Nanowire Studied by Coherent X-ray Diffraction. Nano Letters, 2013, 13, 1883-1889.	4.5	23
77	Fast pole figure acquisition using area detectors at the DiffAbs beamline – Synchrotron SOLEIL. Journal of Applied Crystallography, 2013, 46, 1842-1853.	1.9	47
78	Comparative study of metallic silicide–germanide orthorhombic MnP systems. Journal of Physics Condensed Matter, 2013, 25, 355403.	0.7	3
79	Efficient parametric amplification in micro-resonators with integrated piezoelectric actuation and sensing capabilities. Applied Physics Letters, 2013, 102, .	1.5	34
80	<i>In situ</i> three-dimensional reciprocal-space mapping during mechanical deformation. Journal of Synchrotron Radiation, 2012, 19, 688-694.	1.0	27
81	An upper bound for validity limits of asymptotic analytical approaches based on normal form theory. Nonlinear Dynamics, 2012, 70, 1931-1949.	2.7	28
82	Thermoelasticity and interdiffusion in CuNi multilayers. Physical Review B, 2012, 85, .	1.1	7
83	Performance of piezoelectric shunts for vibration reduction. Smart Materials and Structures, 2012, 21, 015008.	1.8	141
84	Expected and unexpected plastic behavior at the micron scale: An in situ $\hat{l}^{1}\!\!/_{4}$ Laue tensile study. Acta Materialia, 2012, 60, 1252-1258.	3.8	38
85	Finite element reduced order models for nonlinear vibrations of piezoelectric layered beams with applications to NEMS. Finite Elements in Analysis and Design, 2012, 49, 35-51.	1.7	78
86	Placement and dimension optimization of shunted piezoelectric patches for vibration reduction. Journal of Sound and Vibration, 2012, 331, 3286-3303.	2.1	98
87	In situ combined synchrotron X-ray diffraction and wafer curvature measurements during formation of thin palladium silicide film on Si(001) and Si (111). Nuclear Instruments & Methods in Physics Research B, 2012, 284, 74-77.	0.6	5
88	Local strain induced in silicon by Si3N4 lines: Modeling and experimental investigation via X-ray diffraction. Nuclear Instruments & Methods in Physics Research B, 2012, 284, 23-28.	0.6	3
89	Contamination levels of human pharmaceutical compounds in French surface and drinking water. Journal of Environmental Monitoring, 2011, 13, 2929.	2.1	50
90	First-principles study of nickel-silicides ordered phases. Journal of Alloys and Compounds, 2011, 509, 2639-2644.	2.8	52

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91	Nanometer Scale Assessment of Mechanical Strain Induced in Silicon by a Periodic Line Array. Journal of Nanoscience and Nanotechnology, 2011, 11, 9160-9166.	0.9	1
92	Transition to chaotic vibrations for harmonically forced perfect and imperfect circular plates. International Journal of Non-Linear Mechanics, 2011, 46, 234-246.	1.4	51
93	Effect of non-ideal clamping shape on the resonance frequencies of silicon nanocantilevers. Nanotechnology, 2011, 22, 245501.	1.3	32
94	Dislocation storage in single slip-oriented Cu micro-tensile samples: new insights via X-ray microdiffraction. Philosophical Magazine, 2011, 91, 1256-1264.	0.7	43
95	3D strain imaging in sub-micrometer crystals using cross-reciprocal space measurements: Numerical feasibility and experimental methodology. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 388-393.	0.6	6
96	Post Si(C)N hillock nucleation and growth in IC copper lines controlled by diffusional creep. Microelectronic Engineering, 2010, 87, 361-364.	1.1	7
97	X-ray microbeam strain investigation on Cu–MEMS structures. Microelectronic Engineering, 2010, 87, 394-397.	1.1	8
98	Nickel silicide encroachment formation and characterization. Microelectronic Engineering, 2010, 87, 245-248.	1.1	32
99	Out-of-plane stresses arising from grain interactions in textured thin films. Acta Materialia, 2010, 58, 2452-2463.	3.8	16
100	Finite element simulations of coherent diffraction in elastoplastic polycrystalline aggregates. Comptes Rendus Physique, 2010, 11, 293-303.	0.3	4
101	A harmonic-based method for computing the stability of periodic solutions of dynamical systems. Comptes Rendus - Mecanique, 2010, 338, 510-517.	2.1	103
102	Structural Vibration Reduction by Switch Shunting of Piezoelectric Elements: Modeling and Optimization. Journal of Intelligent Material Systems and Structures, 2010, 21, 797-816.	1.4	50
103	Lattice instabilities in hexagonal NiSi: A NiAs prototype structure. Physical Review B, 2010, 81, .	1.1	4
104	Optimization of Shunted Piezoelectric Patches for Vibration Reduction of Complex Structures: Application to a Turbojet Fan Blade. , 2010, , .		5
105	Forced Vibrations of Circular Plates: From Periodic to Chaotic Motions. , 2010, , .		1
106	A Harmonic-Based Method for Computing the Stability of Periodic Oscillations of Non-Linear Structural Systems. , 2010, , .		10
107	Methodology for studying strain inhomogeneities in polycrystalline thin films during (i) in situ (i) thermal loading using coherent x-ray diffraction. New Journal of Physics, 2010, 12, 035018.	1.2	24
108	Relation between strain and composition in coherent epitaxial Cu/Ni multilayers: Influence of strong concentration gradients. Physical Review B, 2009, 79, .	1.1	4

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109	Vibrations of an elastic structure with shunted piezoelectric patches: efficient finite element formulation and electromechanical coupling coefficients. International Journal for Numerical Methods in Engineering, 2009, 80, 235-268.	1.5	119
110	High-resolution X-ray diffraction as a tool to investigate the evolution of local stress in sub-micrometric Si lines isolated by periodic arrays of oxide-filled trenches. Materials Science in Semiconductor Processing, 2009, 12, 64-70.	1.9	1
111	Non-linear vibrations of imperfect free-edge circular plates and shells. European Journal of Mechanics, A/Solids, 2009, 28, 500-515.	2.1	34
112	First-principles study of the structural, electronic, vibrational, and elastic properties of orthorhombic NiSi. Physical Review B, 2009, 79, .	1.1	202
113	Flambage et vibrations non-linéaires d'une plaque stratifiée piézoélectrique. Application à un capteur de masse MEMS. Mecanique Et Industries, 2009, 10, 311-316.	0.2	0
114	Self-aligned nickel–platinum silicide oxidation. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2008, 154-155, 155-158.	1.7	5
115	Texture and strain in narrow copper damascene interconnect lines: An X-ray diffraction analysis. Microelectronic Engineering, 2008, 85, 2175-2178.	1.1	5
116	Local strains induced in silicon channel by a periodic array of nitride capped poly lines investigated by high resolution X-ray diffraction. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2008, 154-155, 129-132.	1.7	2
117	Geometrically nonlinear flexural vibrations of plates: In-plane boundary conditions and some symmetry properties. Journal of Sound and Vibration, 2008, 315, 569-590.	2.1	41
118	Reduced-order models for large-amplitude vibrations of shells including in-plane inertia. Computer Methods in Applied Mechanics and Engineering, 2008, 197, 2030-2045.	3.4	42
119	Influence of crystallographic orientation on local strains in silicon: A combined high-resolution X-ray diffraction and finite element modelling investigation. Thin Solid Films, 2008, 516, 8042-8048.	0.8	9
120	Nitrogen impurity effects on nickel silicide formation at low temperatures – New "nitrogen co-plasma―approach. Microelectronic Engineering, 2008, 85, 2005-2008.	1.1	7
121	Diffraction analysis of elastic strains in micro and nanostructures. Zeitschrift Fýr Kristallographie, 2008, 223, 569-574.	1.1	4
122	Applicability of an iterative inversion algorithm to the diffraction patterns from inhomogeneously strained crystals. Physical Review B, 2008, 78, .	1.1	35
123	Effect of Imperfections and Damping on the Type of Nonlinearity of Circular Plates and Shallow Spherical Shells. Mathematical Problems in Engineering, 2008, 2008, 1-19.	0.6	10
124	Structural Vibration Reduction Optimization by Switch Shunting of Piezoelectric Elements. , 2007, , 339.		1
125	Strain field in silicon on insulator lines using high resolution x-ray diffraction. Applied Physics Letters, 2007, 90, 111914.	1.5	40
126	Inversion of the diffraction pattern from an inhomogeneously strained crystal using an iterative algorithm. Physical Review B, 2007, 76, .	1.1	70

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127	Local strain in a 3D nano-crystal revealed by 2D coherent X-ray diffraction imaging. Thin Solid Films, 2007, 515, 5557-5562.	0.8	9
128	Impact of surface preparation on nickel–platinum alloy silicide phase formation. Microelectronic Engineering, 2007, 84, 2523-2527.	1.1	14
129	Investigation by High Resolution X-ray Diffraction of the local strains induced in Si by periodic arrays of oxide filled trenches. Physica Status Solidi (A) Applications and Materials Science, 2007, 204, 2542-2547.	0.8	13
130	Non-linear vibrations of free-edge thin spherical shells: Experiments on a 1:1:2 internal resonance. Nonlinear Dynamics, 2007, 49, 259-284.	2.7	38
131	Comparison of Galerkin, POD and Nonlinear-Normal-Modes Models for Nonlinear Vibrations of Circular Cylindrical Shells., 2006, , 373.		0
132	Numerical modeling of stress build up during nickel silicidation under anisothermal annealing. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2006, 135, 95-102.	1.7	6
133	X-ray scattering: A powerful probe of lattice strain in materials with small dimensions. Applied Surface Science, 2006, 253, 182-187.	3.1	7
134	Non-linear behaviour of free-edge shallow spherical shells: Effect of the geometry. International Journal of Non-Linear Mechanics, 2006, 41, 678-692.	1.4	40
135	Mechanical characterization of low-k and barrier dielectric thin films. Microelectronic Engineering, 2005, 82, 368-373.	1.1	27
136	Nonlinear vibrations and chaos in gongs and cymbals. Acoustical Science and Technology, 2005, 26, 403-409.	0.3	36
137	Pipe-diffusion ripening of Si precipitates in Al-0.5%Cu-1%Si thin films. Philosophical Magazine, 2005, 85, 3541-3552.	0.7	8
138	Combined synchrotron x-ray diffraction and wafer curvature measurements during Ni–Si reactive film formation. Applied Physics Letters, 2005, 87, 041904.	1.5	40
139	Simulation et d $ ilde{A}$ ©termination par rayons X des contraintes dans des micro-composants mod $ ilde{A}$ 'les. European Physical Journal Special Topics, 2004, 118, 109-115.	0.2	0
140	Stresses and interfacial structure in Au–Ni and Ag–Cu metallic multilayers. Scripta Materialia, 2004, 50, 717-721.	2.6	15
141	Exploring Ni–Si thin-film reactions by means of simultaneous synchrotron X-Ray diffraction and substrate curvature measurements. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2004, 114-115, 67-71.	1.7	12
142	In situ study of stress evolution during the reaction of a nickel film with a silicon substrate. Microelectronic Engineering, 2004, 76, 318-323.	1.1	22
143	Hardening/softening behaviour in non-linear oscillations of structural systems using non-linear normal modes. Journal of Sound and Vibration, 2004, 273, 77-101.	2.1	152
144	Asymptotic non-linear normal modes for large-amplitude vibrations of continuous structures. Computers and Structures, 2004, 82, 2671-2682.	2.4	44

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145	In situstress measurements during the growth at different temperatures of Ag–Cu(111) multilayers. Journal of Applied Physics, 2004, 95, 1152-1161.	1.1	4
146	Hidden Isosbestic Point(s) in Ultraviolet Spectra. Applied Spectroscopy, 2004, 58, 486-490.	1.2	31
147	Asymmetric non-linear forced vibrations of free-edge circular plates. Part II: experiments. Journal of Sound and Vibration, 2003, 265, 1075-1101.	2.1	85
148	Impact of thermal cycling on the evolution of grain, precipitate and dislocation structure in Al, 0.5% Cu, 1% Si thin films. Microelectronic Engineering, 2003, 70, 447-454.	1.1	10
149	Simulation of local mechanical stresses in lines on substrate. Microelectronic Engineering, 2003, 70, 455-460.	1.1	8
150	First stages of silicidation in Ti/Si thin films. Microelectronic Engineering, 2003, 70, 166-173.	1.1	4
151	In-situ study of stress evolution during solid state reaction of Pd with Si(001) using synchrotron radiation. Microelectronic Engineering, 2003, 70, 436-441.	1.1	6
152	X-ray diffraction from inhomogeneous thin films of nanometre thickness: modelling and experiment. Journal of Applied Crystallography, 2003, 36, 154-157.	1.9	9
153	Stresses arising from a solid state reaction between palladium films and Si(001) investigated byin situcombined x-ray diffraction and curvature measurements. Journal of Applied Physics, 2003, 94, 1584-1591.	1.1	32
154	Influence of Si substrate orientation on stress development in Pd silicide films grown by solid-state reaction. Applied Physics Letters, 2003, 83, 1334-1336.	1.5	20
155	Thermal expansion and stress development in the first stages of silicidation in Ti/Si thin films. Journal of Applied Physics, 2003, 94, 7083-7090.	1.1	8
156	Interplay between Anisotropic Strain Relaxation and Uniaxial Interface Magnetic Anisotropy in Epitaxial Fe Films on (001) GaAs. Physical Review Letters, 2003, 90, 017205.	2.9	128
157	Cubic local order around Al and intermixing in short-period AlN/TiN multilayers studied by Al K-edge extended x-ray absorption fine structure spectroscopy and x-ray diffraction. Applied Physics Letters, 2003, 82, 3659-3661.	1.5	13
158	Non-linear oscillations of continuous systems with quadratic and cubic non-linerities using non-linear normal modes., 2003,, 701-704.		0
159	Influence of segregation on the measurement of stress in thin films. Journal of Applied Physics, 2002, 91, 2951-2958.	1.1	9
160	ASYMMETRIC NON-LINEAR FORCED VIBRATIONS OF FREE-EDGE CIRCULAR PLATES. PART 1: THEORY. Journal of Sound and Vibration, 2002, 258, 649-676.	2,1	97
161	Chemically diffuse interface in (1 1 1) Au–Ni multilayers: an anomalous X-ray diffraction analysis. Applied Surface Science, 2002, 188, 110-114.	3.1	5
162	Microstructural analysis of AU/NI multilayers interfaces by SAXS and STM. Applied Surface Science, 2002, 188, 182-187.	3.1	12

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163	In situ study of strain evolution during thin film Ti/Al(Si,Cu) reaction using synchrotron radiation. Microelectronic Engineering, 2002, 64, 81-89.	1.1	2
164	Chemical vapor deposition of silicon–germanium heterostructures. Journal of Crystal Growth, 2000, 216, 171-184.	0.7	32
165	Stress, porosity measurements and corrosion behaviour of AIN films deposited on steel substrates. Thin Solid Films, 2000, 359, 221-227.	0.8	34
166	Raman spectra of TiN/AlN superlattices. Thin Solid Films, 2000, 380, 252-255.	0.8	43
167	Interdependence of elastic strain and segregation in metallic multilayers: An x-ray diffraction study of (111) Au/Ni multilayers. Journal of Applied Physics, 2000, 87, 1172-1181.	1.1	50
168	Asymptotic behaviour of stress establishment in thin films. Surface Science, 2000, 465, L764-L770.	0.8	30
169	Segregation and strain relaxation in Au/Ni multilayers: An in situ experiment. Applied Physics Letters, 1999, 75, 914-916.	1.5	27
170	Interdependence between strain relaxation and segregation in Au/Ni multilayers. Journal of Magnetism and Magnetic Materials, 1999, 198-199, 593-595.	1.0	0
171	Limits of validity of the crystallite group method in stress determination of thin film structures. Thin Solid Films, 1998, 319, 9-15.	0.8	42
172	Structure characterization of metallic multilayers by symmetric and asymmetric X-ray diffraction. Thin Solid Films, 1998, 319, 78-80.	0.8	8
173	Effect of Co, Pt, and Au additions on the stability and epitaxy of NiSi2 films on (111)Si. Journal of Applied Physics, 1998, 84, 2583-2590.	1.1	66
174	Twinning behaviour in YBCO and PBCO thin films and in PBCO-YBCO superlattices. Journal of Alloys and Compounds, 1997, 251, 322-327.	2.8	6
175	Structural and magnetic properties of Ni/Cr multilayers. Journal of Magnetism and Magnetic Materials, 1997, 165, 205-207.	1.0	3
176	The composition analysis of YBa 2 Cu 3 O 7-δ or PrBa 2 Cu 3 O 7-δ thin films and (YBa 2 Cu 3 O 7-δ/PrBa 2 Cu) Tj 1061-1065.	j ETQq0 0 0 1.5	0 rgBT /Overlo 2
177	Twinning orientation in YBa2Cu3O7â^'x films deposited on YAlO3 substrates. Applied Physics Letters, 1996, 69, 1942-1944.	1.5	11
178	Influence of the microstructure on the residual strains in (111) Au/Ni multilayers. Journal of Magnetism and Magnetic Materials, 1996, 156, 31-32.	1.0	1
179	Microstructure and residual stresses in (111) multilayers. Thin Solid Films, 1996, 275, 29-34.	0.8	6
180	Field modulated microwave absorption in YBa2Cu3O7/PrBa2Cu3O7 multilayers. Journal of Low Temperature Physics, 1996, 105, 1061-1066.	0.6	1

#	Article	IF	CITATIONS
181	Formation of Ni silicide from Ni(Au) films on (111)Si. Journal of Applied Physics, 1996, 79, 4078.	1.1	46
182	Residual Stresses in Metallic Multilayers. European Physical Journal Special Topics, 1996, 06, C7-125-C7-134.	0.2	2
183	Mechanical and Microstructural Studies of (111) Au/Ni Multilayers. European Physical Journal Special Topics, 1996, 06, C7-135-C7-142.	0.2	1
184	Microwave properties of YBCO thin films. IEEE Transactions on Applied Superconductivity, 1995, 5, 1737-1740.	1.1	22
185	Growth of (YBaCuO) < sub > m < /sub > /(PrBaCuO) < sub > n < /sub > Superlattices by MOCVD. European Physical Journal Special Topics, 1995, 05, C5-423-C5-430.	0.2	2
186	Measurements of critical currents as a function of temperature in YBa2Cu3O7-xthin films: a comparative study. Superconductor Science and Technology, 1994, 7, 195-205.	1.8	7
187	Thermal modelization and experiments on the current of superconducting microbridges dependence to light in the 10–90K range. Physica B: Condensed Matter, 1994, 194-196, 2125-2126.	1.3	1
188	Texture influence on critical current density of YBCO films deposited on (100)-MgO substrates. Physica C: Superconductivity and Its Applications, 1994, 235-240, 627-628.	0.6	12
189	YBa2Cu3O7â^'x thin film deposition by MOCVD for microwave applications. Physica C: Superconductivity and Its Applications, 1994, 235-240, 653-654.	0.6	1
190	Transmission electron microscopy studies of thin films of YBa2Cu3O7-x. Physica C: Superconductivity and Its Applications, 1994, 235-240, 655-656.	0.6	1
191	Growth of YBa2Cu3O7â^'x / PrBa2Cu3O7â^'x heterostructures by chemical vapor deposition. Physica C: Superconductivity and Its Applications, 1994, 235-240, 723-724.	0.6	2
192	Diffusion of elements implanted in amorphous titanium disilicide. Applied Surface Science, 1993, 73, 167-174.	3.1	3
193	Low temperature specific heat measurements of VSi2, NbSi2 and TaSi2. Applied Surface Science, 1993, 73, 232-236.	3.1	4
194	Low temperature specific heat of VSi2, NbSi2, and TaSi2. Journal of Low Temperature Physics, 1993, 92, 335-351.	0.6	35
195	Electrical and optical properties of silicide single crystals and thin films. Materials Science and Engineering Reports, 1993, 9, 141-200.	5.8	94
196	Preparation of YBa2Cu3O7â^'xfilms and YBa2Cu3O7â^'x/Y2O3multilayers using coevaporation and atomic oxygen. Journal of Applied Physics, 1993, 73, 3096-3098.	1.1	11
197	Thinâ€film growth and compositional effects in YBa2Cu3O7â^'xlayers prepared by metalorganic chemical vapor deposition. Journal of Applied Physics, 1993, 74, 4631-4642.	1.1	35
198	Preparation of YBa2Cu3O7 films by low pressure MOCVD using liquid solution sources. European Physical Journal Special Topics, 1993, 03, C3-321-C3-328.	0.2	6

#	Article	IF	CITATIONS
199	Dopant diffusion in silicides: Effect of diffusion paths. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1992, 10, 907-911.	0.9	6
200	Superconductivity in TaSi2 single crystals. Physical Review B, 1992, 45, 4803-4806.	1.1	27
201	Superconducting properties of YBa2Cu3O7â^'x films deposited by chemical vapor deposition. Physica C: Superconductivity and Its Applications, 1991, 185-189, 2113-2114.	0.6	2
202	Flux line decoration and magnetic properties of YBa2Cu3O7 single crystals. Physica C: Superconductivity and Its Applications, 1991, 185-189, 2349-2350.	0.6	2
203	{110} Twinning mechanism in YBa2Cu3O7â^Î. Physica C: Superconductivity and Its Applications, 1991, 185-189, 545-546.	0.6	2
204	The reaction of scandium thin films with silicon: diffusion, nucleation, resistivities. Applied Surface Science, 1991, 53, 138-146.	3.1	15
205	Diffusion of dopants in tungsten disilicide: effects of diffusion paths. Applied Surface Science, 1991, 53, 165-170.	3.1	5
206	Low temperature specific heat of CoSi2. Applied Surface Science, 1991, 53, 240-242.	3.1	3
207	Some transport properties of single crystals of group Va transition metal disilicides. Applied Surface Science, 1991, 53, 247-253.	3.1	26
208	Resistivity and magnetoresistance of monocrystalline TaSi2 and VSi2. Surface and Coatings Technology, 1991, 45, 237-243.	2.2	12
209	Some titanium germanium and silicon compounds: Reaction and properties. Journal of Materials Research, 1990, 5, 1453-1462.	1.2	66
210	Oxidation and formation mechanisms in disilicides: VSi2and CrSi2, inert marker experiments and interpretation. Journal of Applied Physics, 1990, 68, 6213-6223.	1.1	8
211	Oxidation of titanium, manganese, iron, and niobium silicides: Marker experiments. Journal of Applied Physics, 1990, 68, 5133-5139.	1.1	24
212	Respective mobilities of metal and silicon in disilicides: Bilayers of chromium with molybdenum or tungsten. Journal of Applied Physics, 1990, 67, 2410-2414.	1.1	11
213	A.c. characterization of pyrosol and C.V.D. made high Tc materials. Journal of the Less Common Metals, 1990, 164-165, 1393-1399.	0.9	9
214	Organometallic chemical vapor deposition of superconducting YBa2Cu3O7 \hat{a}^{-1} films. Journal of the Less Common Metals, 1990, 164-165, 444-450.	0.9	19
215	Mechanisms for success or failure of diffusion barriers between aluminum and silicon. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1989, 7, 875-880.	0.9	36
216	A comparison between aluminum and copper interactions with highâ€temperature oxide and nitride diffusion barriers. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1989, 7, 784-789.	0.9	36

#	Article	IF	CITATIONS
217	Reaction of titanium with germanium and siliconâ€germanium alloys. Applied Physics Letters, 1989, 54, 228-230.	1.5	68
218	Analysis of the electrical resistivity of Ti, Mo, Ta, and W monocrystalline disilicides. Journal of Applied Physics, 1989, 65, 1584-1590.	1.1	43
219	lon-implantation-induced fluorine agglomeration in tungsten disilicide prepared by low-pressure chemical vapour deposition. Nuclear Instruments & Methods in Physics Research B, 1989, 40-41, 595-598.	0.6	1
220	Nucleation and growth in the reaction of titanium with germanium and some silicon-germanium alloys. Applied Surface Science, 1989, 38, 27-36.	3.1	41
221	Some properties of CrxV1â^'xSi2 and CrxMo1â^'xSi2 thin films. Applied Surface Science, 1989, 38, 94-105.	3.1	4
222	Metallurgical reinvestigation of rare earth silicides. Applied Surface Science, 1989, 38, 156-161.	3.1	53
223	A new route for the deposition of YBaCuO thin films. Physica C: Superconductivity and Its Applications, 1989, 162-164, 137-138.	0.6	0
224	The high residual resistivity of CoSi2: Evidence for a homogeneity range. Applied Surface Science, 1989, 38, 88-93.	3.1	8
225	Bilayers with chromium disilicide: Chromium-vanadium. Applied Surface Science, 1989, 38, 106-116.	3.1	7
226	Comparison of the diffusion barrier properties of tungsten films prepared by hydrogen and silicon reduction of tungsten hexafluoride. Thin Solid Films, 1989, 171, 343-357.	0.8	13
227	Interfacial reactions between Al and RuO2, MoOxand WNxdiffusion barriers on Si. Surface and Interface Analysis, 1989, 14, 7-12.	0.8	7
228	Comment on â€~â€~Evidence for Si diffusion through epitaxial NiSi2grown on Si(111)'' [Appl. Phys. Lett.501257 (1987)]. Applied Physics Letters, 1988, 52, 2269-2269.	0 _{1.5}	7
229	Magnetic and transmission electron microscopy studies of the formation of cobalt silicide thin films. Journal of Applied Physics, 1988, 64, 3014-3017.	1.1	7
230	The diffusion of elements implanted in films of cobalt disilicide. Journal of Applied Physics, 1988, 64, 2973-2980.	1.1	61
231	Diffusion of Sb, Ga, Ge, and (As) in TiSi2. Journal of Applied Physics, 1988, 63, 5335-5345.	1.1	49
232	Diffusion of boron, phosphorus, and arsenic implanted in thin films of cobalt disilicide. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1988, 6, 1736-1739.	0.9	19
233	Low-temperature specific heat ofMoSi2. Physical Review B, 1988, 37, 10364-10366.	1.1	11
234	Reacted amorphous layers: Tantalum and niobium oxides. The Philosophical Magazine: Physics of Condensed Matter B, Statistical Mechanics, Electronic, Optical and Magnetic Properties, 1988, 58, 529-538.	0.6	14

#	Article	IF	CITATION
235	de Haas–van Alphen effect inMoSi2. Physical Review B, 1987, 35, 7936-7938.	1.1	18
236	Crystal growth, characterization and resistivity measurements of TiSi2 single crystals. Journal of the Less Common Metals, 1987, 136, 175-182.	0.9	23
237	Optical properties of WSi2 and MoSi2 single crystals as measured by spectroscopic ellipsometry and reflectometry. Solid State Communications, 1987, 62, 455-459.	0.9	32
238	Electronic properties of CoSi2 studied by reflectivity and spectroscopic ellipsometry. Solid State Communications, 1986, 60, 923-926.	0.9	26
239	Resistivity and magnetoresistance of high-purity monocrystalline MoSi2. Journal of Physics F: Metal Physics, 1986, 16, 1745-1752.	1.6	28
240	Molybdenum disilicide: Crystal growth, thermal expansion and resistivity. Solid State Communications, 1985, 55, 629-632.	0.9	114